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	Filing Date	2003-12-08
	First Named Inventor	Gilbert C. Vandling
	Art Unit	2825
	Examiner Name	Vuthe Siek
Attorney Docket Number		1019.P003US

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DUP	1	P. GIRALD, "A Trace-Based Method for Delay Fault Diagnosis in Synchronous Sequential Circuit", IEEE, 1995 pages 526-532, Montpellier Cedex 05, France.	<input type="checkbox"/>
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